CLAIMS

- 1 1. A keam shearing system comprising:
- 2 an entrance slit structure having an entrance
- 3 slit extending in a first direction for receiving a
- slat extending in a beam of light having a photon flux within a
- 5 predetermined spectral pass band;
- a beam splitter aligned at an angle to the first
- 7 direction so that the received beam of light is split
- 8 into two separate beams; and
- g a reflective subsystem having a plurality of
- 10 reflective surfaces defining separate light paths of
- 11 equal optical path length for the two separate beams,
- the reflective surfaces arranged such that when the
- two beams emerge from the beam shearing system they
- ophtain more than 50 percent of the said photon flux
- and the chief rays of the two separate beams are
- substantially parallel to each other.
- 1 2. The beam shearing system in claim 1 wherein:
- said two beams emerging from the beam shearing
- 3 system contain substantially all of the light entering
- 4 the system through the entrance slit.
- 1 3. The beam shearing system in claim 1 wherein:
- said two light paths being of substantially equal
- 2 said two light factors of the optical path length and causing the wave fronts of the

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1	two separate beams to remain substantially in phas
2	relative to one another.

- 1-4. The beam shearing system in claim 1 wherein:
- said plurality of reflective surfaces are further
- arranged so that the separate beams of light are of
- 4 substantially equal intensity, when they emerge from
- 5 the beam shearing system.
- 1 5. The beam shearing system in claim 1 wherein:
- the reflective subsystem comprises a plurality of
- 3 bodies with a beam splitter therebetween; and
- the entrance and exit surfaces of the plurality
- of bodies are substantially perpendicular to the chief
- 6 ray of the received beam of light.
- 1 6. A spectral resolving system comprising:
- an entrance slit structure having an entrance
- 3 slit extending in a first direction for receiving a
- 4 beam of light having a photon flux within a
- 5 predetermined spectral pass band;
- 6 a beam shearing system including:
- 7 a beam splitter aligned at an angle to the
- 8 first direction so that the received beam of
- 9 light is split into two separate beams;

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1	a reflective subsystem having a plurality of
	reflective surfaces defining separate light paths
2	of equal optical path length for the two separate
3	of equal optical pach length 132 of that
4	beams, the reflective surfaces arranged such that
+	when the two beams emerge from the beam shearing
5	when the two peaks sharpy
6	system they contain more than 50 percent of the
	said photon flux and the chief rays of the two
7	separate beams are substantially parallel to each
8	separate beams are substantially pass
9	other; and
,	the said two separate
10	ar optical system focusing the said two separate
	the said beam shearing

an optical system focusing the said two separate beams of light emerging from the said beam shearing system onto an exit pupil.

- 1 7. The spectral resolving system of claim 6 wherein:
- sati optical system also focuses the said separate beams of light emerging from the said beam shearing system to create an image.
 - 8. The spectral resolving system of claim 7 wherein:
- 2 said optical system has an optical axis;
- said exit pupil is located in one of the group consisting of a targential plane and a sagiital plane relative to the said beam shearing system;
- said image is located in the other of the group
 consisting of a tangential plane and a sagiital plane
 relative to the said beam shearing system; and

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- 2 substantially the same position along the optical
- axis.
- 1 9. The spectral resolving system of claim 6 wherein:
- the optical system is telecentric in the said
- 3 exit pupil plane.
- 1 10. The spectral resolving system of claim 6 wherein:
- the optical system is anamorphic.
- 1 11. The spectral resolving system of claim 6 wherein:
- the said optical system cancels aberrations when
- 3 it recembines the two beams of light that emerge from
- 4 the beam shearing system.
- 1 12. A static interferemeter comprising:
- 2 fore-optics for collecting light and focusing it
- into a beam;
- 4 a spectral resolving system comprising:
- an entrance slit structure having an
- 6 entrance slit extending in a first direction for
- 7 receiving a beam of light having a photon flux
- 8 within a predetermined spectral pass band;
- a beam shearing system including:

	a beam splitter aligned at an angle co
1	the first direction so that the received
2	beam of light is split into two separate
3	beam of figure is spire as
4	beams;
-	a reflective subsystem having a
5	plurality of reflective surfaces defining
6	separate light paths of equal optical path
7	length for the two separate beams, the
8	length for the two our control
9	reflective sulfaces arranged such shearing
10	the two beams emerge from the beam shearing
11	system they contain more than 50 percent of
12	the said photon flux and the chief rays of
	the two separate beams are substantially
13	parallel to each other; and
14	transing the said two
15	an optical system focusing the said two
16	separate beams of light emerging from the said
17	beam shearing system onto an exit pupil; and
1 /	a detector located at the exit pupil.
18	a detector rocatod do una elementaria de la companya de la company

- 1 13. The static interferometer in claim 12 wherein:
- the detector comprises a detector array, read out electronics and a data processing system.
- 1 14. The static interferometer in claim 13 wherein:
 2 the detector array records the intensity of the
- 2 the detector array 13 radiation incident on its pixels;

the read out electronics digitizes	the	intensity
measurements made by the detector array	arıd	transfers
them to the data processing system; and		
them to the data processing of		

the data processing system manipulates the digitized measurements to obtain information about the spectrum of said incident radiation.

1 15. The static interferometer in claim 14 wherein:

the data processing system performs Fast Fourier
Transforms on the digitized measurements to obtain the
spectral composition of the incident radiation;

1 16. The static interferometer in claim 14 wherein:

the data processing system convolves the digitated measurements with digital filters to detect the presence or absence in the spectrum of the incident radiation of frequencies of radiation characteristically emitted or absorbed by particular substances.

- 1 17. The static interferometer in claim 12 wherein:
- 2 a single sided interferogram is created at said exit pupil.
- 1 18. The static interferometer in claim 17 wherein:
- the fore-optics fecus the collected light in such
- a way that the chief ray of the said collected light
- 4 describes paths through the said spectral resolving
- system, which recombine on the said exit pupil at the
- 6 edge of the said detector array; and
- 7 said paths of the chief ray have substantially
- the same optical path length.
- 1 19. The static interferemeter in claim 18 wherein:
- said fore-optics have a shifted pupil design.
- 1 20. The static interferometer in claim 12 wherein:
- said fore-optics are telecentric.
- 1 21. The static interferometer of claim 12 wherein:
- 2 said optical system also focuses the said
- 3 separate beams of light emerging from the said beam
- 4 shearing system to create an image.

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22.	The	static	interferometer	of	claim	21	wherein:
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said optical system has an optical axis;

said exit pupil is located in one of the group

consisting of a tangential plane and a sagiital plane

relative to the said beam shearing system;

said image is located in the other of the group consisting of a tangential plane and a sagiital plane relative to the said beam shearing system; and

the exit pupil and the image are located at substantially the same position along the optical axis.

23. A beam shearing system comprising:

an entrance slit structure having an entrance slit extending in a first direction for receiving a beam of light having a photon flux within a predetermined spectral pass band;

a keam splitter aligned at an angle to the first direction so that the received beam of light is split into two separate beams;

a reflective subsystem having a plurality of reflective surfaces defining separate light paths of equal optical path length for the two separate beams, the reflective surfaces arranged such that one of the separate beams undergoes one reflection and the other of the separate beams undergoes three reflections and

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that when the two	a beams emerde	from the	beam	shea	aring
that when the two	beams charge	50 percen	it of	the	said
system they cont	ain more unan	OO Longer			
photon flux.					

24. A static interferometer comprising:

	fore-optics for collecting light and collimating
2	fore-optios for outling rossessing an exit pupil;
3	into a beam, the fore-optics possessing an exit pupil;
4	a spectral resolving system comprising:
4	an entrance slit structure having an
5	an entrance site is fixet direction for
6	entrance slit extending in a first direction for
7	receiving a beam of light having a photon flux
8	within a predetermined spectral pass band;

a beam shearing system comprising:

a beam splitter aligned at an angle to the first direction so that the received beam of light is split into two separate beams;

a reflective subsystem having a plurality of reflective surfaces defining separate light paths of equal optical path length for the two separate beams, the reflective surfaces arranged such that one of the separate beams undergoes one reflection and the other of the separate beams undergoes three reflections and that when the two beams emerge from the beam

	shearing system they contain more than s	5(1
1	shearing system on percent of the said photon flux; and	
,	percent of the salu fire	h.e

- a detector located at said exit pupil where the two beams emerging from the beam shearing system
- converge.
 - 25. The static interferometer in claim 24 wherein:
- the detector comprises a detector array, read
- out electronics and a data processing system. 3
- The static interferemeter in claim 25 wherein: 26.
- the detector array records the intensity of the 2
- radiation incident on its pixels;
- the read out electronics digitizes the intensity 4
- measurements made by the detector array and transfers 5
- them to the data processing system; and
- the data processing system manipulates 7
- digitized measurements to obtain information about the
- spectrum of said incident radiation. 9
- 27. The static interferometer in claim 26 wherein:
- the data processing system performs Fast Fourier 2
- Transforms on the digitized measurements to obtain the
- spectral composition of the incident radiation;

28.	The	static	interferometer	in	claim	27	wherein:
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- data processing system convolves the the 2
- digitized measurements with digital filters to detect 3
- the presence or absence in the spectrum of the
- incident radiation of frequencies of radiation 5
- characteristically emitted or absorbed by particular
- substancés. 7
- 29. The static interferometer in claim 24 which further
- comprises: 2
- an anamorphic optical system possessing an 3
- optical axis; 4
- the exit pupil being perpendicular to the optical 5
- axis;
- the optical system focusing the two 7
- emerging from the beam shearing system to create an 8
- image; and 9
- the image being perpendicular to the exit pupil 10
- and perpendicular to the optical axis. 11